

Resource Summary Report

Generated by RRID on Aug 5, 2026

JEOL: JSM-7900F Field Emission Scanning Electron Microscope (SEM)

RRID:SCR_020191

Type: Tool

Proper Citation

JEOL: JSM-7900F Field Emission Scanning Electron Microscope (SEM)
(RRID:SCR_020191)

Resource Information

URL: <https://www.jeolusa.com/PRODUCTS/Scanning-Electron-Microscopes-SEM/FE-SEM/JSM-7900F>

Proper Citation: JEOL: JSM-7900F Field Emission Scanning Electron Microscope (SEM)
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Description: Scanning electron microscope with flexible platform that combines high resolution imaging with nano scale microanalysis.

Resource Type: instrument resource

Keywords: Jeol, JEOL, Scanning Electron Microscope, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: JEOL: JSM-7900F Field Emission Scanning Electron Microscope (SEM)

Resource ID: SCR_020191

Alternate IDs: Model_Number_JSM_7900F

Record Creation Time: 20220129T080349+0000

Record Last Update: 20260801T190653+0000

Ratings and Alerts

No rating or validation information has been found for JEOL: JSM-7900F Field Emission Scanning Electron Microscope (SEM).

No alerts have been found for JEOL: JSM-7900F Field Emission Scanning Electron Microscope (SEM).

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.